

**Test Lab
Attestation Letter**

Date of Test: July 9, 2015 ~ July 10, 2015

Applicant Name: SAMSUNG ELECTRONICS CO., LTD.

FCC Id: A3LSLC430

**Name of Engineer
Performing Test:** Young Jin Kim

Statement of Compliance: (Test Lab) declares that this Unit has been tested in accordance with the test method identified in this test report and that we observed it being tested. It also declares that the Unit complies with the relevant limits. All instrumentation and accessories used to test this unit for compliance to the indicated test method are calibrated regularly in accordance with ISO 17025:2005 requirements by laboratories accredited by A2LA, NVLAP, or ACLAS for the measurement parameters.

The measurements were made at: Samsung Electronics EMC Laboratory
(Maetan dong) 129, Samsung-ro, Yeongtong-Gu, Suwon-Si,
Gyeonggi-Do, South Korea

Test Lab Witness-

Signature of Test Lab Witness:



Full Name, Typed: Chan Ho Youn

Title of Witness: Manager

Email Address: jjano.youn@samsung.com

Phone No.: +1-973-808-6362

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